



Recent Advances and Applications of Infrared Thermography

Guest Editor:

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Deadline for manuscript
submissions:

closed (31 January 2020)

Message from the Guest Editor

Dear Colleagues,

Infrared thermography (IRT), as a non-destructive evaluation method, has been applied for the last five decades with great success in a broad spectrum of disciplines. Due to the continuous advances in sensor technology and electronics, IRT has evolved into a major, accurate, versatile, and well-established method for various applications. Defect detection, thermal performance of buildings, monitoring of damage, diagnosis of medical conditions, art authenticity evaluation, assessment of culture heritage conditions, and many other applications have led the scientific community to develop and advance numerous methodologies based on infrared thermography. This Special Issue of *Applied Sciences* focuses on the recent advances and applications of infrared thermography in a variety of disciplines. The aim of this issue is to attract research involving novel and advanced IRT methodologies or/and new applications that have an impact on the scientific community. Manuscripts that combine IRT with other non-destructive methodologies, as long as IRT is the main method, are also welcome.

Dr. Evangelos Z. Kordatos
Guest Editor





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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